## **AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (currently amended) A substrate for an information recording medium, which is formed of a glass containing, by mol%:

45 to 70 % of SiO<sub>2</sub>, 1 to 15 % of Al<sub>2</sub>O<sub>3</sub>, total content of SiO<sub>2</sub> and Al<sub>2</sub>O<sub>3</sub> being 57 to 85 %;

2 to 25 % of CaO, more than 0 but not more than 15 % of BaO, 0 to 15 % of MgO, 0 to 15 % of SrO, 0 to 10 % of ZnO, the total content of MgO, CaO, SrO, BaO and ZnO being 2 to 30 %;

more than 0 % but not more than 15 % of K<sub>2</sub>O, more than 0 but not more than 8 % of Na<sub>2</sub>O, total content of K<sub>2</sub>O and Na<sub>2</sub>O being 2 to 15 %;

more than 0 but not more than 12 % of ZrO<sub>2</sub>, 0 to 10 % of TiO<sub>2</sub>, ratio of content of CaO to the total content of MgO, CaO, SrO and BaO (CaO/(MgO+CaO+SrO+BaO)) is 0.5% or more; the total content of SiO<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub>, MgO, CaO, SrO, BaO, ZnO, K<sub>2</sub>O, Na<sub>2</sub>O, ZrO<sub>2</sub>, TiO<sub>2</sub>

components in the glass being at least 95 mol%, the glass contains no Li<sub>2</sub>O, has a glass transition temperature (Tg) of 600°C or higher and an etching rate of 0.1 <u>µl</u>/minute or less with regard to a hydrosilicofluoric acid aqueous solution maintained at a temperature of 45°C with the hydrosilicofluoric acid concentration of 1.72 % by weight.

2.-3. (canceled).

IKENISHI, M. et al. Appl. No. 10/505,282 June 25, 2009

- 4. (withdrawn) The substrate for an information recording medium as recited in claim 1, wherein the glass contains SiO<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub>, CaO, Na<sub>2</sub>O and K<sub>2</sub>O and has a chemically strengthened layer.
- 5. (withdrawn) The substrate for an information recording medium as recited in claim 4, wherein the glass has a composition comprising, by mol%, 47 to 70 % of SiO<sub>2</sub>, 1 to 10 % of Al<sub>2</sub>O<sub>3</sub>, the total content of SiO<sub>2</sub> and Al<sub>2</sub>O<sub>3</sub> being 57 to 80 %, 1 to 15 % of BaO, 1 to 10 % of Na<sub>2</sub>O, the total content of Na<sub>2</sub>O, K<sub>2</sub>O and Li<sub>2</sub>O being 3 to 16 %, 1 to 12 % of ZrO<sub>2</sub>, 0 to 10 % of MgO, 0 to 15 % of SrO, 0 to 10 % of ZnO, the total content of MgO, CaO, SrO, BaO and ZnO being 3 to 30 %, the ratio of the content of CaO to the total content of MgO, CaO, SrO and BaO being at least 0.5, and 0 to 10 % of TiO<sub>2</sub>, the total content of said components being at least 95 mol%.
- 6. (withdrawn) The substrate for an information recording medium as recited in claim 1, wherein the glass contains SiO<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub>, CaO, BaO, Na<sub>2</sub>O and ZrO<sub>2</sub> as essential components and has a chemically strengthened layer,
- 7. (withdrawn) The substrate for an information recording medium as recited in claim 6, wherein the glass has a composition comprising, by mol%, 47 to 70 % of SiO<sub>2</sub>, 1 to 10 % of Al<sub>2</sub>O<sub>3</sub>, the total content of SiO<sub>2</sub> and Al<sub>2</sub>O<sub>3</sub> being 57 to 80 %, 2 to 25 % of CaO, 1 to 15 % of BaO, 1 to 10 % of Na<sub>2</sub>O, more than 0 but not more than 15 % of K<sub>2</sub>O, 0 to 3 % of Li<sub>2</sub>O, the total content of Na<sub>2</sub>O, K<sub>2</sub>O and Li<sub>2</sub>O being 3 to 16 %, 1 to 12 % of ZrO<sub>2</sub>, 0 to 10 % of MgO, 0 to 15 % of SrO, 0 to 10 % of ZnO, the total content of MgO, CaO, SrO, BaO and ZnO being 3 to 30 %, the ratio of the content of CaO to the total content of MgO, CaO, SrO and BaO being at least 0.5, and 0 to 10 % of TiO<sub>2</sub>, the total content of said components being at least 95 mol%.

8. (withdrawn) The substrate for an information recording medium as recited in claim 1, which is for use in a perpendicular-magnetic-recording-mode information recording medium.

- 9. (withdrawn) An information recording medium having an information recording layer formed on the substrate for an information recording medium recited in claim 1.
- 10. (withdrawn) The information recording medium as recited in claim 9, which is a perpendicular-magnetic-recording-mode magnetic recording medium.
- 11. (withdrawn) A process for manufacturing an information recording medium, which comprises the step of forming an information recording layer on a substrate for an information recording medium and uses the substrate for an information recording medium recited in claim 1 as said substrate, said step comprising the procedure of heating said substrate to a temperature of 300 to 600°C.
  - 12.-13. (canceled).
- 14. (withdrawn) An information recording medium having an information recording layer formed on the substrate for an information recording medium recited in claim 4.
- 15. (withdrawn) An information recording medium having an information recording layer formed on the substrate for an information recording medium recited in claim 5.
- 16. (withdrawn) An information recording medium having an information recording layer formed on the substrate for an information recording medium recited in claim 6.
- 17. (withdrawn) An information recording medium having an information recording layer formed on the substrate for an information recording medium recited in claim 7.
  - 18. (canceled).
- 19. (currently amended) The substrate for an information recording medium as recited in claim 1, wherein the glass has a composition comprising, by mol%, 50 to 67 % of SiO<sub>2</sub>, 2 to 12

IKENISHI, M. et al. Appl. No. 10/505,282 June 25, 2009

% of Al<sub>2</sub>O<sub>3</sub>, the total content of SiO<sub>2</sub> and Al<sub>2</sub>O<sub>3</sub> being 57 to 79 %, 3 to 20 % of CaO, more than 0 but not more than 14% of BaO, 0 to 10 % of MgO, more than 0 but not more than 0 to 10 % of SrO, 0 to 8 % of ZnO, the total content of MgO, CaO, SrO, BaO and ZnO being 3 to 30 %, more than 0 but not more than 5 % of Na<sub>2</sub>O, 0.5 % to 15 % of K<sub>2</sub>O, the total content of K<sub>2</sub>O and Na<sub>2</sub>O being 4 to 12 %, more than 0 but not more than 10 % of ZrO<sub>2</sub> and 0 to 8 % of TiO<sub>2</sub>.